CLAIMS:

manner and that has an electrical circuit (2), to which circuit (2) the signal (S) can be fed and which circuit (2) is arranged to generate a supply voltage (V) for parts of the circuit (2) by using the signal (S), which circuit (2) comprises storage means (5) that are arranged to store information capacitively, the information being represented by a value of an information voltage (UI) arising at the storage means (5), which value of the information voltage (UI) is at most equal to the value of the supply voltage (V), and which circuit (2) has evaluation means (14) to which the information voltage (UI) can be fed and that are arranged to evaluate the information voltage (UI), with the help of a comparison voltage (UC), for the information represented by the information voltage (UI), characterized in that comparison-voltage generating means (15) that are arranged to generate and emit the comparison voltage (UC) are implemented separately from the evaluation means (14), and in that the evaluation means (14) are arranged to receive the comparison voltage (UC) from the comparison-voltage generating means (15).

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2. A data carrier (1) as claimed in claim 1, characterized in that the evaluation means (14) are formed by a difference amplifier stage (16), which difference amplifier stage (16) is intended to amplify the difference between the information voltage (UI) and the comparison voltage (UC).

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3. A data carrier as claimed in claim 1, characterized in that the circuit (2) has a test terminal (T) from which a representation of the information voltage (UI) can be picked off, and in that the evaluation means (14) are arranged to make the information voltage (UI) available at the test terminal (T) in a way that can be controlled.

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4. A data carrier (1) as claimed in claim 1, characterized in that the comparison-voltage generating means (15) are arranged to take account of a value of the supply voltage (V) when generating the comparison voltage (UC).

- A data carrier (1) as claimed in claim 1, characterized in that the comparison-5. voltage generating means (15) are arranged to generate the comparison voltage (UC) in a programmable manner.
- A circuit (2) for a data carrier (1), which data carrier (1) is arranged to receive 5 6. a signal (S) in a non-contacting manner, which circuit (2) is arranged, by using the signal (S), to generate a supply voltage (V) for parts of the circuit (2), which circuit (2) comprises storage means (5) that are arranged to store information capacitively, the information being represented by a value of an information voltage (UI) arising at the storage means (5), which value of the information voltage (UI) is at most equal to the value of the supply voltage (V), 10 and which circuit (2) has evaluation means (14) to which the information voltage (UI) can be fed and that are arranged to evaluate the information voltage (UI), with the help of a comparison voltage (UC), for the information represented by the information voltage (UI), characterized in that comparison-voltage generating means (15) that are arranged to generate and emit the comparison voltage (UC) are implemented separately from the evaluation means 15 (14), and in that the evaluation means (14) are arranged to receive the comparison voltage (UC) from the comparison-voltage generating means (15).
- A circuit (2) as claimed in claim 6, characterized in that the evaluation means 7. (14) are formed by a difference amplifier stage (16), which difference amplifier stage (16) is 20 intended to amplify the difference between the information voltage (UI) and the comparison voltage (UC).
- A circuit (2) as claimed in claim 6, characterized in that the circuit (2) has a 8. test terminal (T) from which a representation of the information voltage (UI) can be picked 25 off, and in that the evaluation means (14) are arranged to make the information voltage (UI) available at the test terminal (T) in a way that can be controlled.
- A circuit (2) as claimed in claim 6, characterized in that the information-9. voltage generating means (15) are arranged to take account of a value of the supply voltage 30 (V) when generating the comparison voltage (UC).

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- 10. A circuit (2) as claimed in claim 6, characterized in that the comparison-voltage generating means (15) are arranged to generate the comparison voltage (UC) in a programmable manner.
- 5 11. A circuit (2) as claimed in claim 6, characterized in that the circuit (2) is implemented in the form of an integrated circuit.